

Application/Control No.
10/807,667
Examiner

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/807,667	CHEE ET AL.		
Examiner	Art Unit		
B. Clayton McCraw	3744		

SEARCHED					
Class	Subclass	Date	Examiner		
62	175,305,3 14	10/22/2005	всм		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted with Primary Examiner, William Doerrler	10/22/2005	всм
Conducted Inventor Name Search	10/22/2005	всм
Consulted with Acting Supervisory Patent Examiner, Melba Bumgarner	10/22/2005	всм
EAST Search Notes Attached	10/24/2005	всм
EAST Interference Search Attached	4/12/2006	всм